Marko J Tadjer

List of Publications by Year in Descending Order

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The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

80
papers

3,295
citations

26
p-index

83
ext. papers

3,8
ext. citations

3,8
avg, IF

56
g-index

5.62
L-index

#	Paper	IF	Citations
80	A review of band structure and material properties of transparent conducting and semiconducting oxides: Ga2O3, Al2O3, In2O3, ZnO, SnO2, CdO, NiO, CuO, and Sc2O3. <i>Applied Physics Reviews</i> , 2022 , 9, 011315	17.3	27
79	Thermal effects in Ga2O3 rectifiers and MOSFETs borrowing from GaN 2022, 441-467		
78	Reduced-stress nanocrystalline diamond films for heat spreading in electronic devices 2022 , 275-294		
77	A perspective on the electro-thermal co-design of ultra-wide bandgap lateral devices. <i>Applied Physics Letters</i> , 2021 , 119, 170501	3.4	8
76	Two-step growth of EGa2O3 films on (100) diamond via low pressure chemical vapor deposition. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2021, 39, 023411	2.9	6
75	Steady-state methods for measuring in-plane thermal conductivity of thin films for heat spreading applications. <i>Review of Scientific Instruments</i> , 2021 , 92, 044907	1.7	2
74	Engineering the Spectral and Spatial Dispersion of Thermal Emission via Polariton-Phonon Strong Coupling. <i>Nano Letters</i> , 2021 , 21, 1831-1838	11.5	16
73	Design of Ga2O3 modulation doped field effect transistors. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 2021 , 39, 023412	2.9	4
7 2	Collective Phonon-Polaritonic Modes in Silicon Carbide Subarrays ACS Nano, 2021,	16.7	4
71	Band offset determination for amorphous Al2O3 deposited on bulk AlN and atomic-layer epitaxial AlN on sapphire. <i>Applied Physics Letters</i> , 2020 , 117, 182103	3.4	1
70	Narrowband Polaritonic Thermal Emitters Driven by Waste Heat. ACS Omega, 2020 , 5, 10900-10908	3.9	16
69	Integration of polycrystalline Ga2O3 on diamond for thermal management. <i>Applied Physics Letters</i> , 2020 , 116, 062105	3.4	42
68	Electrical Properties 4. <i>Springer Series in Materials Science</i> , 2020 , 443-459	0.9	
67	Diodes 1. Springer Series in Materials Science, 2020 , 661-688	0.9	
66	Structural and electronic properties of Si- and Sn-doped (201) EGa2O3 annealed in nitrogen and oxygen atmospheres. <i>Journal Physics D: Applied Physics</i> , 2020 , 53, 504002	3	10
65	Structural transition and recovery of Ge implanted EGa2O3. Applied Physics Letters, 2020, 117, 152101	3.4	18
64	Band Offsets of Insulating & Semiconducting Oxides on (AlxGa1-x)O3. <i>ECS Transactions</i> , 2019 , 92, 79-86	8 1	5

(2018-2019)

63	High Performance \${beta}\$ -Ga2O3 Nano-Membrane Field Effect Transistors on a High Thermal Conductivity Diamond Substrate. <i>IEEE Journal of the Electron Devices Society</i> , 2019 , 7, 914-918	2.3	24	
62	Controlling the threshold voltage of EGa2O3 field-effect transistors via remote fluorine plasma treatment. <i>Journal of Materials Chemistry C</i> , 2019 , 7, 8855-8860	7.1	13	
61	Thermoreflectance Temperature Mapping of Ga2O3 Schottky Barrier Diodes. <i>ECS Transactions</i> , 2019 , 89, 3-7	1	3	
60	GaN-On-Diamond HEMT Technology With TAVG = 176°C at PDC,max = 56 W/mm Measured by Transient Thermoreflectance Imaging. <i>IEEE Electron Device Letters</i> , 2019 , 40, 881-884	4.4	28	
59	Tunable Thermal Energy Transport across Diamond Membranes and Diamond-Si Interfaces by Nanoscale Graphoepitaxy. <i>ACS Applied Materials & Diamond Membranes</i> , 2019 , 11, 18517-18527	9.5	30	
58	Damage Recovery and Dopant Diffusion in Si and Sn Ion Implanted EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , 2019 , 8, Q3133-Q3139	2	20	
57	Valence and Conduction Band Offsets for InN and III-Nitride Ternary Alloys on (201) Bulk EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , 2019 , 8, Q3154-Q3158	2	9	
56	Thermal conductance across EGa2O3-diamond van der Waals heterogeneous interfaces. <i>APL Materials</i> , 2019 , 7, 031118	5.7	63	
55	Editors' ChoiceReviewTheory and Characterization of Doping and Defects in EGa2O3. ECS Journal of Solid State Science and Technology, 2019 , 8, Q3187-Q3194	2	89	
54	Vertical Ga2O3 Schottky Barrier Diodes With Small-Angle Beveled Field Plates: A Baliga Figure-of-Merit of 0.6 GW/cm2. <i>IEEE Electron Device Letters</i> , 2019 , 40, 1399-1402	4.4	84	
53	Defect Characterization of Multicycle Rapid Thermal Annealing Processed p-GaN for Vertical Power Devices. <i>ECS Journal of Solid State Science and Technology</i> , 2019 , 8, P70-P76	2	6	
52	Lateral GaN JFET Devices on Large Area Engineered Substrates. <i>ECS Journal of Solid State Science and Technology</i> , 2019 , 8, Q226-Q229	2	2	
51	Ohmic contacts to gallium oxide 2019 , 211-230		4	
50	Electrical characterization of ALD HfO2 high-k dielectrics on (2001) EGa2O3. <i>Applied Physics Letters</i> , 2018 , 112, 042107	3.4	38	
49	A review of Ga2O3 materials, processing, and devices. <i>Applied Physics Reviews</i> , 2018 , 5, 011301	17.3	1114	
48	(Invited) Fabrication and Characterization of EGa2O3Heterojunction Rectifiers. <i>ECS Transactions</i> , 2018 , 85, 21-26	1	9	
47	Electrothermal Evaluation of AlGaN/GaN Membrane High Electron Mobility Transistors by Transient Thermoreflectance. <i>IEEE Journal of the Electron Devices Society</i> , 2018 , 6, 922-930	2.3	7	
46	Heterostructure WSe-GaO Junction Field-Effect Transistor for Low-Dimensional High-Power Electronics. ACS Applied Materials & amp; Interfaces, 2018, 10, 29724-29729	9.5	60	

45	High resistivity halide vapor phase homoepitaxial EGa2O3 films co-doped by silicon and nitrogen. <i>Applied Physics Letters</i> , 2018 , 113, 192102	3.4	27
44	Cheap Ultra-Wide Bandgap Power Electronics? Gallium Oxide May Hold the Answer. <i>Electrochemical Society Interface</i> , 2018 , 27, 49-52	3.6	18
43	A Tri-Layer PECVD SiN Passivation Process for Improved AlGaN/GaN HEMT Performance. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, P58-P61	2	9
42	Thermionic Emission Analysis of TiN and Pt Schottky Contacts to EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, P165-P168	2	31
41	Quasi-Two-Dimensional h-BN/EGaO Heterostructure Metal-Insulator-Semiconductor Field-Effect Transistor. <i>ACS Applied Materials & amp; Interfaces</i> , 2017 , 9, 21322-21327	9.5	71
40	Dry Etching of High Aspect Ratio 4H-SiC Microstructures. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, P207-P210	2	9
39	Vertical GaN Junction Barrier Schottky Diodes. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, Q10-Q12	2	18
38	Band Alignments of Atomic Layer Deposited ZrO2and HfO2High-k Dielectrics with (-201) EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, Q3052-Q3055	2	57
37	Solar-Blind Metal-Semiconductor-Metal Photodetectors Based on an Exfoliated EGa2O3Micro-Flake. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, Q79-Q83	2	65
36	Deep reactive ion etching of 4H-SiC via cyclic SF6/O2 segments. <i>Journal of Micromechanics and Microengineering</i> , 2017 , 27, 095004	2	12
35	Electrothermal evaluation of thick GaN epitaxial layers and AlGaN/GaN high-electron-mobility transistors on large-area engineered substrates. <i>Applied Physics Express</i> , 2017 , 10, 126501	2.4	10
34	Optical characterization and thermal properties of CVD diamond films for integration with power electronics. <i>Solid-State Electronics</i> , 2017 , 136, 12-17	1.7	13
33	Vertical GaN Junction Barrier Schottky Rectifiers by Selective Ion Implantation. <i>IEEE Electron Device Letters</i> , 2017 , 38, 1097-1100	4.4	96
32	Nanocrystalline diamond capped AlGaN/GaN high electron mobility transistors via a sacrificial gate process. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2016 , 213, 893-897	1.6	17
31	Selective p-type Doping of GaN:Si by Mg Ion Implantation and Multicycle Rapid Thermal Annealing. <i>ECS Journal of Solid State Science and Technology</i> , 2016 , 5, P124-P127	2	32
30	Structural, Optical, and Electrical Characterization of Monoclinic EGa2O3 Grown by MOVPE on Sapphire Substrates. <i>Journal of Electronic Materials</i> , 2016 , 45, 2031-2037	1.9	92
29	Effect of Reduced Extended Defect Density in MOCVD Grown AlGaN/GaN HEMTs on Native GaN Substrates. <i>IEEE Electron Device Letters</i> , 2016 , 37, 28-30	4.4	38
28	Electrical and Thermal Stability of ALD-Deposited TiN Transition Metal Nitride Schottky Gates for AlGaN/GaN HEMTs. <i>ECS Journal of Solid State Science and Technology</i> , 2016 , 5, Q204-Q207	2	5

(2012-2016)

27	In search of quantum-limited contact resistance: understanding the intrinsic and extrinsic effects on the graphenefinetal interface. <i>2D Materials</i> , 2016 , 3, 025013	5.9	10	
26	Homoepitaxial growth of EGa2O3 thin films by low pressure chemical vapor deposition. <i>Applied Physics Letters</i> , 2016 , 108, 182105	3.4	145	
25	Heteroepitaxy of N-type EGa2O3 thin films on sapphire substrate by low pressure chemical vapor deposition. <i>Applied Physics Letters</i> , 2016 , 109, 132103	3.4	96	
24	Enhancement mode AlGaN/GaN MOS high-electron-mobility transistors with ZrO2gate dielectric deposited by atomic layer deposition. <i>Applied Physics Express</i> , 2016 , 9, 071003	2.4	21	
23	Impact of Surface Passivation on the Dynamic ON-Resistance of Proton-Irradiated AlGaN/GaN HEMTs. <i>IEEE Electron Device Letters</i> , 2016 , 37, 545-548	4.4	23	
22	Editors' Choice Communication (001) EGa2O3MOSFET with +2.9 V Threshold Voltage and HfO2Gate Dielectric. ECS Journal of Solid State Science and Technology, 2016, 5, P468-P470	2	106	
21	Elimination of Basal Plane Dislocations in Epitaxial 4H-SiC via Multicycle Rapid Thermal Annealing. <i>Materials Science Forum</i> , 2015 , 821-823, 297-302	0.4	1	
20	Thermal etching of nanocrystalline diamond films. <i>Diamond and Related Materials</i> , 2015 , 59, 116-121	3.5	8	
19	MnO2-Based Electrochemical Supercapacitors on Flexible Carbon Substrates. <i>Journal of Electronic Materials</i> , 2014 , 43, 1188-1193	1.9	14	
18	Thermionic-Field Emission Barrier Between Nanocrystalline Diamond and Epitaxial 4H-SiC. <i>IEEE Electron Device Letters</i> , 2014 , 35, 1173-1175	4.4	2	
17	Large-Signal RF Performance of Nanocrystalline Diamond Coated AlGaN/GaN High Electron Mobility Transistors. <i>IEEE Electron Device Letters</i> , 2014 , 35, 1013-1015	4.4	24	
16	Proton Radiation-Induced Void Formation in Ni/Au-Gated AlGaN/GaN HEMTs. <i>IEEE Electron Device Letters</i> , 2014 , 35, 1194-1196	4.4	23	
15	Impact of Intrinsic Stress in Diamond Capping Layers on the Electrical Behavior of AlGaN/GaN HEMTs. <i>IEEE Transactions on Electron Devices</i> , 2013 , 60, 3149-3156	2.9	25	
14	Atomic Layer Epitaxy AlN for Enhanced AlGaN/GaN HEMT Passivation. <i>IEEE Electron Device Letters</i> , 2013 , 34, 1115-1117	4.4	39	
13	Nanocrystalline Diamond-Gated AlGaN/GaN HEMT. IEEE Electron Device Letters, 2013, 34, 1382-1384	4.4	13	
12	GaN Power Transistors with Integrated Thermal Management. ECS Transactions, 2013, 58, 279-286	1	3	
11	Degradation of dynamic ON-resistance of AlGaN/GaN HEMTs under proton irradiation 2013,		12	
10	. IEEE Electron Device Letters, 2012 , 33, 23-25	4.4	83	

9	Comparative Study of Ohmic Contact Metallizations to Nanocrystalline Diamond Films. <i>Materials Science Forum</i> , 2010 , 645-648, 733-735	0.4	4
8	On the high curvature coefficient rectifying behavior of nanocrystalline diamond heterojunctions to 4H-SiC. <i>Applied Physics Letters</i> , 2010 , 97, 193510	3.4	6
7	Technique for the dry transfer of epitaxial graphene onto arbitrary substrates. ACS Nano, 2010, 4, 1108-	- 16 .7	163
6	Electrical and Optical Characterization of AlGaN/GaN HEMTs with In Situ and Ex Situ Deposited SiN x Layers. <i>Journal of Electronic Materials</i> , 2010 , 39, 2452-2458	1.9	22
5	An AlN/Ultrathin AlGaN/GaN HEMT Structure for Enhancement-Mode Operation Using Selective Etching. <i>IEEE Electron Device Letters</i> , 2009 , 30, 1251-1253	4.4	24
4	Influence of Shockley Stacking Fault Expansion and Contraction on the Electrical Behavior of 4H-SiC DMOSFETs and MPS diodes. <i>Materials Research Society Symposia Proceedings</i> , 2008 , 1069, 1		1
3	Thermal Annealing and Propagation of Shockley Stacking Faults in 4H-SiC PiN Diodes. <i>Journal of Electronic Materials</i> , 2007 , 36, 318-323	1.9	26
2	Influence of Shockley stacking fault propagation and contraction on electrical behavior of 4H-SiC pin diodes and DMOSFETs 2007 ,		1
1	Nanocrystalline diamond films as UV-semitransparent Schottky contacts to 4H-SiC. <i>Applied Physics</i>	3.4	18